Precision Operational Amplifier, 25 μV Offset, Zero-Drift, 36 V Supply, 2 MHz

NCS21911, NCV21911, NCS21912, NCV21912, NCS21914, NCV21914

The NCS2191x family of high precision op amps feature low input offset voltage and near–zero drift over time and temperature. These op amps operate over a wide supply range from 4 V to 36 V with low quiescent current. The rail–to–rail output swings within 10 mV of the rails. The family includes the single channel NCS(V)21911, the dual channel NCS(V)21912, and the quad channel NCS(V)21914 in a variety of packages. All versions are specified for operation from –40°C to +125°C. Automotive qualified options are available under the NCV prefix.

Features

- Input Offset Voltage: ±25 μV max
- Zero-Drift Offset Voltage: ±0.085 μV/°C max
- Voltage Noise Density: 22 nV/√Hz typical
- Unity Gain Bandwidth: 2 MHz typical
- Supply Voltage: 4 V to 36 V
- Quiescent Current: 570 μA max
- Rail-to-Rail Output
- NCV Prefix for Automotive and Other Applications Requiring Unique Site and Control Change Requirements; AEC-Q100 Qualified and PPAP Capable
- These Devices are Pb-free, Halogen free/BFR free and are RoHS compliant

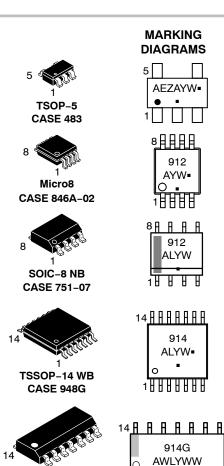
Typical Applications

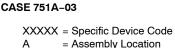
- Temperature Measurements
- Transducer Applications
- Electronic Scales
- Medical Instrumentation
- Current Sensing
- Automotive



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SOIC-14 NB

L or WL = Wafer Lot
Y = Year
W = Work Week
= Pb-Free Package

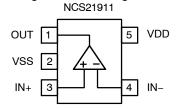
(Note: Microdot may be in either location)

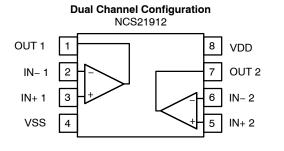
ORDERING INFORMATION

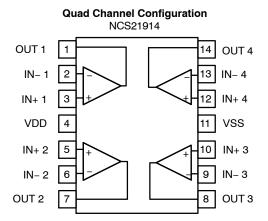
See detailed ordering and shipping information on page 2 of this data sheet.

PIN CONNECTIONS

Single Channel Configuration







ORDERING INFORMATION

Channels	Device	Package	Shipping †
Single	NCS21911SN2T1G	SOT23-5 / TSOP-5	3000 / Tape & Reel
Dual	NCS21912DR2G	SOIC-8	2500 / Tape & Reel
	NCS21912DMR2G	MICRO-8	4000 / Tape & Reel
Quad	NCS21914DR2G	SOIC-14	2500 / Tape & Reel
	NCS21914DTBR2G	TSSOP-14	2500 / Tape & Reel
Automotive Quali	ified		
Channels	Device	Package	Shipping [†]
Single	NCV21911SN2T1G	SOT23-5 / TSOP-5	3000 / Tape & Reel
Dual	NCV21912DR2G	SOIC-8	2500 / Tape & Reel
	NCV21912DMR2G	MICRO-8	4000 / Tape & Reel
Quad	NCV21914DR2G	SOIC-14	2500 / Tape & Reel
	NCV21914DTBR2G	TSSOP-14	2500 / Tape & Reel

[†]For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specification Brochure, BRD8011/D.

ABSOLUTE MAXIMUM RATINGS

Parameter	Rating	Unit
Supply Voltage (VDD- VSS)	40	V
INPUT AND OUTPUT PINS		
Input Voltage (Note 1)	VSS – 0.3 to VDD + 0.3	V
Differential Input Voltage (Note 2)	±17	V
Input Current (Notes 1 and 2)	±10	mA
Output Short Circuit Current (Note 3)	Continuous	mA
TEMPERATURE	<u>.</u>	
Operating Temperature	-40 to +125	°C
Storage Temperature	-65 to +150	°C
Junction Temperature	+150	°C
ESD RATINGS (Note 4)		
Human Body Model (HBM)	3000	V
Charged Device Model (CDM)	2000	V
OTHER RATINGS	•	
Latch-up Current (Note 5)	100	mA
MSL	Level 1	

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

- 1. Input terminals are diode-clamped to the power-supply rails. Input signals that can swing more than 0.3 V beyond the supply rails should be current limited to 10 mA or less.
- 2. The inputs are diode connected with a total input protection of 1.65 k Ω , increasing the absolute maximum differential voltage to $\pm 17 \ V_{DC}$. If the applied differential voltage is expected to exceed this rating, external resistors should be added in series with the inputs to limit the input current to $\pm 10 \ \text{mA}$.
- 3. Short–circuit to V_{DD} or V_{SS} . Short circuits to either rail can cause an increase in the junction temperature. The total power dissipation must be limited to prevent the junction temperature from exceeding the 150°C limit.
- 4. This device series incorporates ESD protection and is tested by the following methods: ESD Human Body Model tested per JEDEC standard JS-001-2017 (AEC-Q100-002) ESD Charged Device Model tested per JEDEC standard JS-002-2014 (AEC-Q100-011)
- 5. Latch-up Current tested per JEDEC standard JESD78E (AEC-Q100-004).

THERMAL INFORMATION (Note 6)

Rating	Symbol	Package	Value	Unit
Thermal Resistance, Junction to Ambient	θ_{JA}	TSOP-5 / SOT23-5	170	°C/W
		Micro8/MSOP8	116	
		SOIC-8	87	
		SOIC-14	59	
		TSSOP-14	78	

As mounted on an 80x80x1.5 mm FR4 PCB with 2S2P, 2 oz copper, and a 200 mm² heat spreader area. Following JEDEC JESD51-7 guidelines.

OPERATING CONDITIONS

Parameter	Symbol	Range	Unit
Supply Voltage (V _{DD} - V _{SS})	V _S	4 to 36	V
Specified Operating Temperature Range	T _A	-40 to 125	°C
Input Common Mode Voltage Range	V _{CM}	V _{SS} to V _{DD} -1.5	V
Differential Voltage (Note 7)	V_{DIFF}	±17	V

The inputs are diode connected with a total input protection of 1.65 kΩ, increasing the absolute maximum differential voltage to ±17 V_{DC}.
 If the applied differential voltage is expected to exceed this rating, external resistors should be added in series with the inputs to limit the input current to ±10 mA.

ELECTRICAL CHARACTERISTICS $V_S = 4 V \text{ to } 36 V$

At $T_A = +25^{\circ}C$, $R_L = 10~k\Omega$ connected to midsupply, $V_{CM} = V_{OUT} =$ midsupply, unless otherwise noted. **Boldface** limits apply over the specified temperature range, $T_A = -40^{\circ}C$ to 125°C, guaranteed by characterization and/or design.

Parameter	Symbol	Conditio	ns	Min	Тур	Max	Unit
INPUT CHARACTERISTICS							
Offset Voltage	Vos				±1	±25	μV
Offset Voltage Drift vs Temp	$\Delta V_{OS}/\Delta T$				±0.02	±0.085	μV/°C
Input Bias Current (Note 8)	I _{IB}				±100	±500	pA
						±3500	pA
Input Offset Current (Note 8)	I _{OS}				±200	±500	pA
						±3500	pA
Common Mode Rejection Ratio	CMRR	$V_{SS} \le V_{CM} \le V_{DD} - 1.5 V$	V _S = 36 V	140	150		dB
		V _{DD} -1.5 V		130			
			V _S = 12 V	130	150		
			(Note 8)	120			
			V _S = 8 V	130	140		
			(Note 8)	120			
			V _S = 4 V	120	130		
			•	110			
Input Capacitance	C _{IN}	Common N	Лode		3		pF
EMI Rejection Ratio	EMIRR	f = 5 GHz f = 400 MHz			100		dB
					80		
OUTPUT CHARACTERISTICS	<u>.</u>	<u>l</u>				<u> </u>	
Open Loop Voltage Gain	A _{VOL}	V _{SS} + 0.5 V < V _O <	: V _{DD} – 0.5 V	130	150		dB
- F	I VOL			125	135		
Open Loop Output Impedance	Z _{OUT OL}	No Load			See		Ω
					Figure 23		
Output Voltage High, Referenced to	V _{OH}	No Load			5	10	mV
Rail		R _L = 10	kΩ		100	210	
					140	250	
Output Voltage Low, Referenced to	V_{OL}	No Loa	d		5	10	mV
Rail		R _L = 10	kΩ		100	210	
					140	250	
Short Circuit Current	I _{SC}	Sinking Cu	rrent		18		mA
		Sourcing C	urrent		16		
Capacitive Load Drive	CL				1		nF
DYNAMIC PERFORMANCE		•					
Gain Bandwidth Product	GBW	C _L = 100	pF		2		MHz
Gain Margin	A _M	C _L = 100 pF			13		dB
Phase Margin	φм	C _L = 100	pF		55		0
Slew Rate	SR	G = +1	-		1.6		V/μs
Settling Time	t _S	V _S = 36 V	0.1%		20		μs
-		_	0.01%		45		μs
Overload Recovery Time	t _{OR}	V _S = ±18 V, A _V	/ = -10,		1		μs
		$V_{IN} = \pm 2$.	5 V				

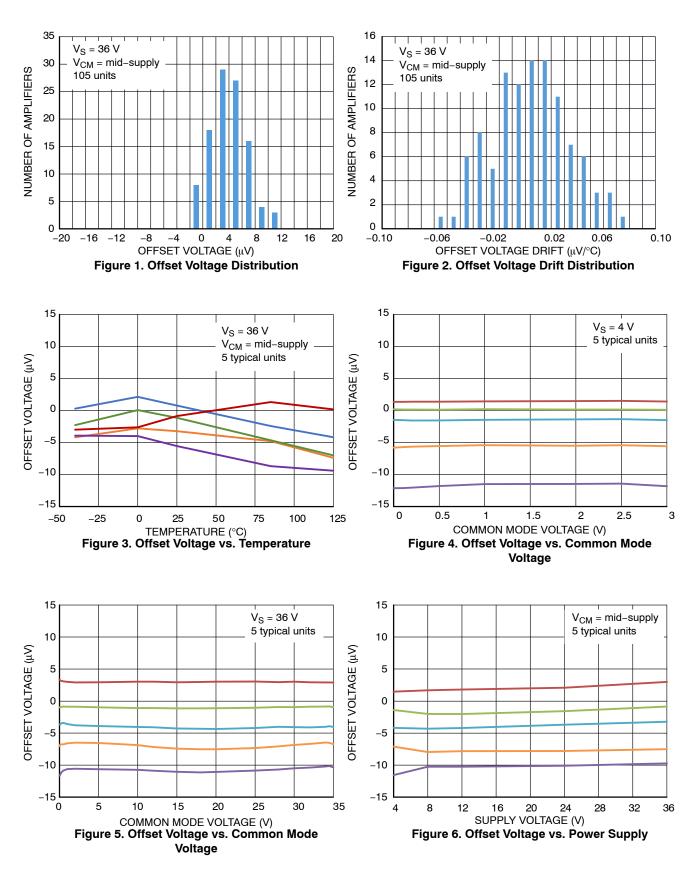
^{8.} Guaranteed by characterization and/or design.

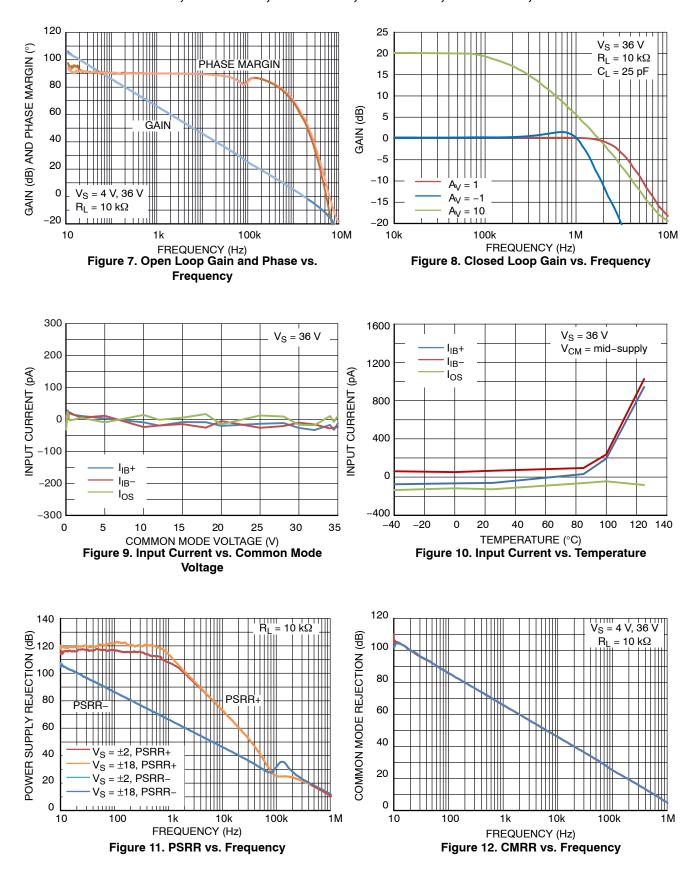
ELECTRICAL CHARACTERISTICS $V_S = 4 \text{ V to } 36 \text{ V}$ At $T_A = +25 ^{\circ}\text{C}$, $R_L = 10 \text{ k}\Omega$ connected to midsupply, $V_{CM} = V_{OUT} =$ midsupply, unless otherwise noted. **Boldface** limits apply over the specified temperature range, $T_A = -40 ^{\circ}\text{C}$ to 125 $^{\circ}\text{C}$, guaranteed by characterization and/or design.

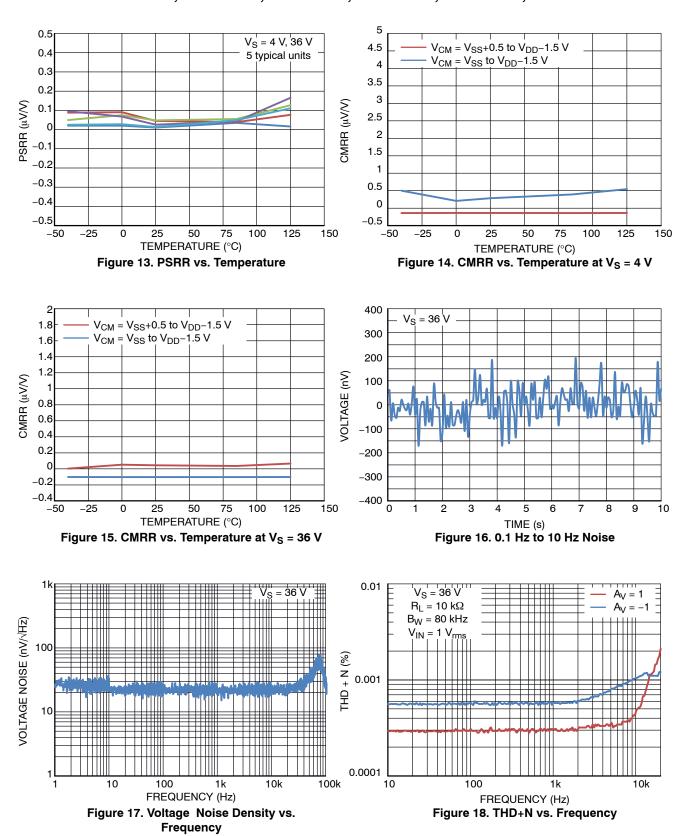
Parameter	Symbol	Conditions	Min	Тур	Max	Unit
NOISE PERFORMANCE						
Total Harmonic Distortion + Noise	THD+N	f_{IN} = 1 kHz, A_V = 1, V_{OUT} = 1 V_{TMS}		0.0003		%
Voltage Noise Density	e _N	f = 1 kHz		22		nV/√ Hz
Current Noise Density	i _N	f = 1 kHz		100		fA/√ Hz
Voltage Noise, Peak-to-Peak	e _{PP}	f = 0.1 Hz to 10 Hz		400		nV_PP
Voltage Noise, RMS	e _{rms}	f = 0.1 Hz to 10 Hz		70		nV_{rms}
POWER SUPPLY						
Power Supply Rejection Ratio	PSRR	V _S = 4 V to 36 V		0.02	0.3	μV/V
			130	154		dB
Quiescent Current	ΙQ	Per channel		475	570	μΑ
					570	1

GRAPHS

Typical performance at $T_A = 25^{\circ}C$, unless otherwise noted.







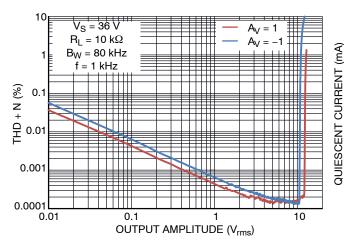


Figure 19. THD+N vs. Output Amplitude

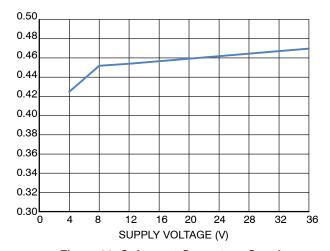


Figure 20. Quiescent Current vs. Supply Voltage

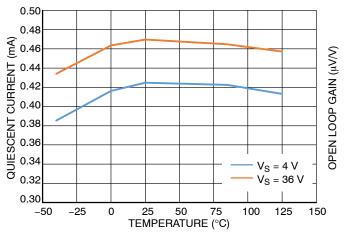


Figure 21. Quiescent Current vs. Temperature

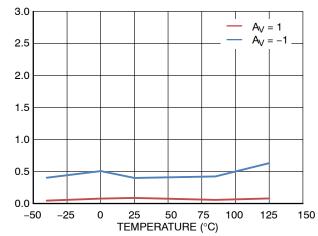


Figure 22. Open Loop Gain vs. Temperature

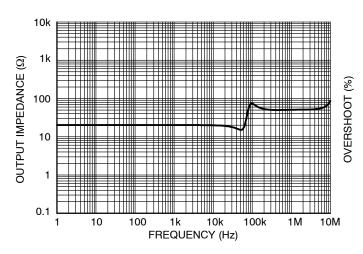


Figure 23. Open Loop Output Impedance vs. Frequency

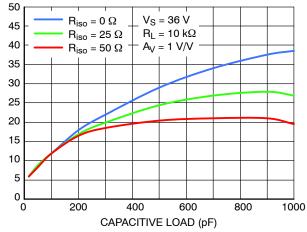


Figure 24. Small Signal Overshoot vs. Capacitive Load (100 mV Output Step)

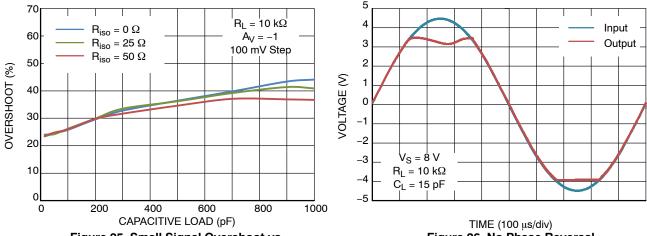


Figure 25. Small Signal Overshoot vs. Capacitive Load (100 mV Output Step)

Figure 26. No Phase Reversal

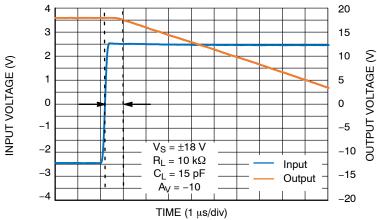


Figure 27. Positive Overload Recovery

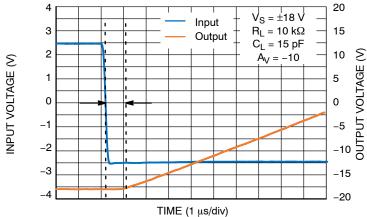
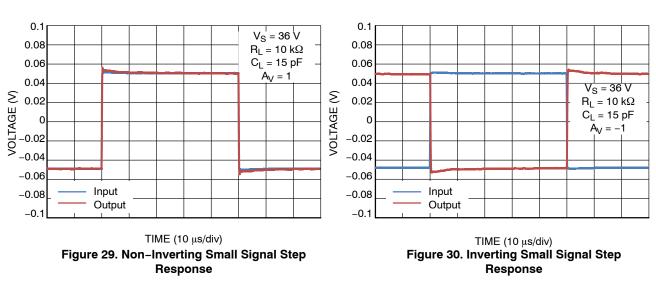
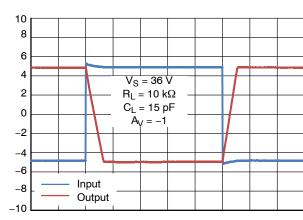


Figure 28. Negative Overload Recovery



10 8 6 4 C_L = 10 kΩ C_L = 15 pF A_V = 1 (Σ) BEATION

TIME (10 μs/div)
Figure 31. Non–Inverting Large Signal Step
Response



TIME (10 μs/div)
Figure 32. Inverting Large Signal Step
Response

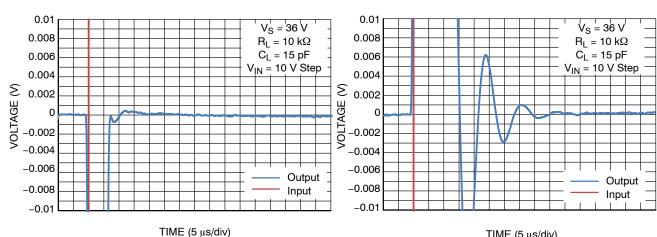


Figure 33. Large Signal Settling Time, Low-to-High

TIME (5 μs/div)
Figure 34. Large Signal Settling Time,
High-to-Low

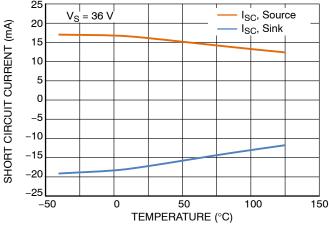


Figure 35. Short Circuit Current vs. Temperature

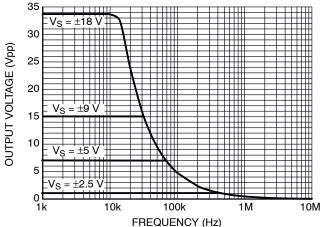


Figure 36. Maximum Output Voltage vs. Frequency ($A_V = 1$ for $V_S = \pm 2.5$ V, ± 5 V, ± 9 V; $A_V = 2$ for $V_S = \pm 18$ V)

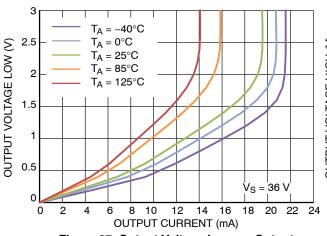


Figure 37. Output Voltage Low vs. Output Current

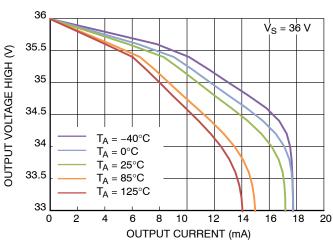


Figure 38. Output Voltage High vs. Output Current

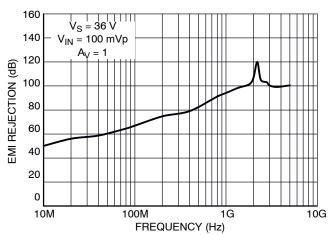


Figure 39. EMIRR IN+ vs. Frequency

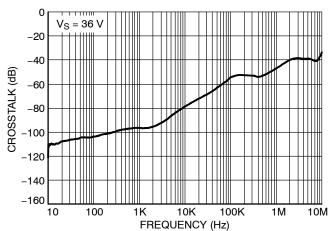


Figure 40. Channel-to-Channel Crosstalk

APPLICATION INFORMATION

Overview

The NCS21911, NCS21912, and NCS21914 precision op amps provide low offset voltage and zero drift over temperature. With a maximum offset voltage of 25 μV and input common mode voltage range that includes ground, the NCS21911 series is well–suited for applications where precision is required, such as low side current sensing and interfacing with sensors.

The NCS21911 series of amplifiers uses a chopper-stabilized architecture, which provides the advantage of minimizing offset voltage drift over temperature and time. The simplified block diagram is shown in Figure 41. Unlike the classical chopper architecture, the chopper stabilized architecture has two signal paths.

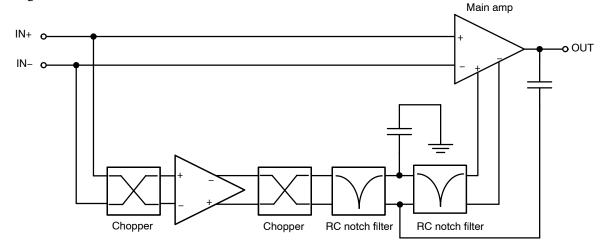


Figure 41. Simplified NCS21911 Block Diagram

In Figure 41, the lower signal path is where the chopper samples the input offset voltage, which is then used to correct the offset at the output. The offset correction occurs at a frequency of 250 kHz. The chopper-stabilized architecture is optimized for best performance at frequencies up to the related Nyquist frequency (1/2 of the offset correction frequency). As the signal frequency exceeds the Nyquist frequency, 125 kHz, aliasing may occur at the output. This is an inherent limitation of all chopper and chopper-stabilized architectures. Nevertheless, the NCS21911 series op amps have minimal aliasing up to 200 kHz and are less susceptible to aliasing effects when compared to competitor parts from other manufacturers. ON Semiconductor's patented approach utilizes two cascaded, symmetrical, RC notch filters tuned to the chopper frequency and its fifth harmonic to reduce aliasing effects.

The chopper-stabilized architecture also benefits from the feed-forward path, which is shown as the upper signal path of the block diagram in Figure 41. This is the high speed signal path that extends the gain bandwidth up to 2 MHz. Not only does this help retain high frequency components of the input signal, but it also improves the loop gain at low frequencies. This is especially useful for low-side current sensing and sensor interface applications where the signal is low frequency and the differential voltage is relatively small.

Application Circuits

Low-Side Current Sensing

Low–side current sensing is used to monitor the current through a load. This method can be used to detect over–current conditions and is often used in feedback control, as shown in Figure 42. A sense resistor is placed in series with the load to ground. Typically, the value of the sense resistor is less than 100 m Ω to reduce power loss across the resistor. The op amp amplifies the voltage drop across the sense resistor with a gain set by external resistors R1, R2, R3, and R4 (where R1 = R2, R3 = R4). Precision resistors are required for high accuracy, and the gain is set to utilize the full scale of the ADC for the highest resolution.

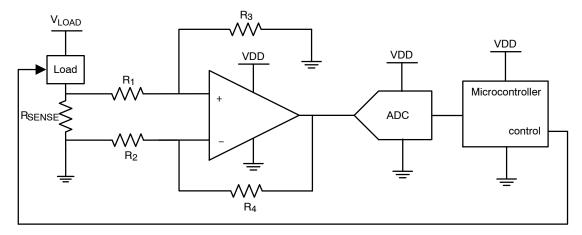


Figure 42. Low-Side Current Sensing

Differential Amplifier for Bridged Circuits

Sensors to measure strain, pressure, and temperature are often configured in a Wheatstone bridge circuit as shown in Figure 43. In the measurement, the voltage change that is

produced is relatively small and needs to be amplified before going into an ADC. Precision amplifiers are recommended in these types of applications due to their high gain, low noise, and low offset voltage.

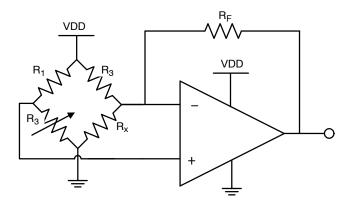


Figure 43. Wheatstone Bridge Circuit Amplification

EMI Susceptibility and Input Filtering

Op amps have varying amounts of EMI susceptibility. Semiconductor junctions can pick up and rectify EMI signals, creating an EMI-induced voltage offset at the output, adding another component to the total error. Input pins are the most sensitive to EMI. The NCS2191x integrates low-pass filters to decrease its sensitivity to EMI. Figure 39 shows the EMIRR performance.

General Layout Guidelines

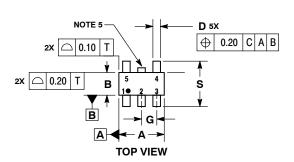
To ensure optimum device performance, it is important to follow good PCB design practices. Place 0.1 µF decoupling

capacitors as close as possible to the supply pins. Keep traces short, utilize a ground plane, choose surface-mount components, and place components as close as possible to the device pins. These techniques will reduce susceptibility to electromagnetic interference (EMI). Thermoelectric effects can create an additional temperature dependent offset voltage at the input pins. To reduce these effects, use metals with low thermoelectric coefficients and prevent temperature gradients from heat sources or cooling fans.

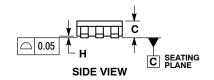


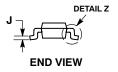
TSOP-5 **CASE 483 ISSUE N**

DATE 12 AUG 2020







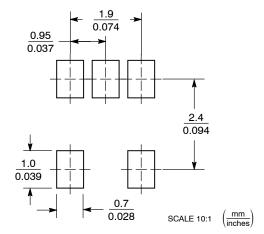


NOTES:

- DIMENSIONING AND TOLERANCING PER ASME
- CONTROLLING DIMENSION: MILLIMETERS.
 MAXIMUM LEAD THICKNESS INCLUDES LEAD FINISH
 THICKNESS. MINIMUM LEAD THICKNESS IS THE
 MINIMUM THICKNESS OF BASE MATERIAL.
- DIMENSIONS A AND B DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.15 PER SIDE. DIMENSION A. OPTIONAL CONSTRUCTION: AN ADDITIONAL
- TRIMMED LEAD IS ALLOWED IN THIS LOCATION. TRIMMED LEAD NOT TO EXTEND MORE THAN 0.2 FROM BODY.

	MILLIMETERS			
DIM	MIN	MAX		
Α	2.85	3.15		
В	1.35	1.65		
C	0.90	1.10		
D	0.25	0.50		
G	0.95	0.95 BSC		
Н	0.01	0.10		
J	0.10	0.26		
K	0.20	0.60		
М	0 °	10 °		
S	2.50	3.00		

SOLDERING FOOTPRINT*



^{*}For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

GENERIC MARKING DIAGRAM*





XXX = Specific Device Code XXX = Specific Device Code

= Assembly Location

= Date Code = Year = Pb-Free Package

= Work Week W

= Pb-Free Package

(Note: Microdot may be in either location)

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " ■", may or may not be present.

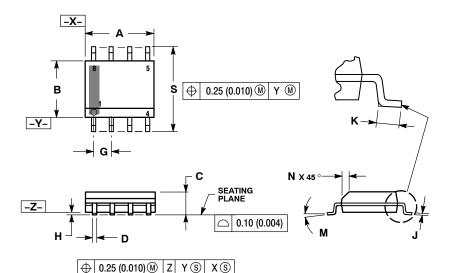
DOCUMENT NUMBER:	98ARB18753C	Electronic versions are uncontrolled except when accessed directly from Printed versions are uncontrolled except when stamped "CONTROLLED"	
DESCRIPTION:	TSOP-5		PAGE 1 OF 1

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SOIC-8 NB CASE 751-07 **ISSUE AK**

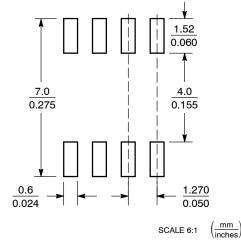
DATE 16 FEB 2011



- NOTES:
 1. DIMENSIONING AND TOLERANCING PER
- ANSI Y14.5M, 1982.
 CONTROLLING DIMENSION: MILLIMETER.
- DIMENSION A AND B DO NOT INCLUDE MOLD PROTRUSION.
- MAXIMUM MOLD PROTRUSION 0.15 (0.006) PER SIDE
- DIMENSION D DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.127 (0.005) TOTAL IN EXCESS OF THE D DIMENSION AT MAXIMUM MATERIAL CONDITION.
- 751-01 THRU 751-06 ARE OBSOLETE. NEW STANDARD IS 751-07.

	MILLIMETERS		INC	HES
DIM	MIN	MAX	MIN	MAX
Α	4.80	5.00	0.189	0.197
В	3.80	4.00	0.150	0.157
C	1.35	1.75	0.053	0.069
D	0.33	0.51	0.013	0.020
G	1.27 BSC		0.050 BSC	
Н	0.10	0.25	0.004	0.010
7	0.19	0.25	0.007	0.010
K	0.40	1.27	0.016	0.050
М	0 °	8 °	0 °	8 °
N	0.25	0.50	0.010	0.020
S	5.80	6.20	0.228	0.244

SOLDERING FOOTPRINT*



^{*}For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

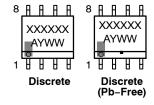
GENERIC MARKING DIAGRAM*



XXXXX = Specific Device Code = Assembly Location = Wafer Lot

= Year = Work Week

= Pb-Free Package



XXXXXX = Specific Device Code = Assembly Location Α

= Year ww

= Work Week = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb–Free indicator, "G" or microdot "■", may or may not be present. Some products may not follow the Generic Marking.

STYLES ON PAGE 2

DOCUMENT NUMBER:	98ASB42564B	Electronic versions are uncontrolled except when accessed directly from the Document Reposi Printed versions are uncontrolled except when stamped "CONTROLLED COPY" in red.		
DESCRIPTION:	SOIC-8 NB		PAGE 1 OF 2	

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SOIC-8 NB CASE 751-07 ISSUE AK

DATE 16 FEB 2011

STYLE 2: PIN 1. COLLECTOR, DIE, #1 2. COLLECTOR, #1 3. COLLECTOR, #2 4. COLLECTOR, #2 6. EMITTER, #2 7. BASE, #1 8. EMITTER, #1 STYLE 6: PIN 1. SOURCE 2. DRAIN 3. DRAIN 4. SOURCE 5. SOURCE 6. GATE 7. GATE 8. SOURCE STYLE 10: PIN 1. GROUND 2. BIAS 1 3. OUTPUT 4. GROUND 5. GROUND 6. PINS 2	STYLE 3: PIN 1. DRAIN, DIE #1 2. DRAIN, #1 3. DRAIN, #2 4. DRAIN, #2 5. GATE, #2 6. SOURCE, #2 7. GATE, #1 8. SOURCE, #1 STYLE 7: PIN 1. IMPUT 2. EXTERNAL BYPASS 3. THIRD STAGE SOURCE 4. GROUND 5. DRAIN 6. GATE 3 7. SECOND STAGE Vd 8. FIRST STAGE Vd STYLE 11: PIN 1. SOURCE 1 2. GATE 1 3. SOURCE 2 4. GATE 2	3. BASE, #2 4. COLLECTOR, #2 5. COLLECTOR, #2 6. EMITTER, #2 7. EMITTER, #1 8. COLLECTOR, #1 STYLE 12: PIN 1. SOURCE 2. SOURCE
PIN 1. SOURCE 2. DRAIN 3. DRAIN 4. SOURCE 5. SOURCE 6. GATE 7. GATE 8. SOURCE STYLE 10: PIN 1. GROUND 2. BIAS 1 3. OUTPUT 4. GROUND	PIN 1. INPUT 2. EXTERNAL BYPASS 3. THIRD STAGE SOURCE 4. GROUND 5. DRAIN 6. GATE 3 7. SECOND STAGE Vd 8. FIRST STAGE Vd STYLE 11: PIN 1. SOURCE 1 2. GATE 1 3. SOURCE 2	PIN 1. COLLECTOR, DIE #1 2. BASE, #1 3. BASE, #2 4. COLLECTOR, #2 5. COLLECTOR, #2 6. EMITTER, #2 7. EMITTER, #1 8. COLLECTOR, #1 STYLE 12: PIN 1. SOURCE 2. SOURCE
PIN 1. GROUND 2. BIAS 1 3. OUTPUT 4. GROUND	PIN 1. SOURCE 1 2. GATE 1 3. SOURCE 2	PIN 1. SOURCE 2. SOURCE
6. BIAS 2 7. INPUT 8. GROUND	5. DRAIN 2 6. DRAIN 2 7. DRAIN 1 8. DRAIN 1	3. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN
STYLE 14: PIN 1. N-SOURCE 2. N-GATE 3. P-SOURCE 4. P-GATE 5. P-DRAIN 6. P-DRAIN 7. N-DRAIN 8. N-DRAIN	STYLE 15: PIN 1. ANODE 1 2. ANODE 1 3. ANODE 1 4. ANODE 1 5. CATHODE, COMMON 6. CATHODE, COMMON 7. CATHODE, COMMON 8. CATHODE, COMMON	STYLE 16: PIN 1. EMITTER, DIE #1 2. BASE, DIE #1 3. EMITTER, DIE #2 4. BASE, DIE #2 5. COLLECTOR, DIE #2 6. COLLECTOR, DIE #2 7. COLLECTOR, DIE #1 8. COLLECTOR, DIE #1
STYLE 18: PIN 1. ANODE 2. ANODE 3. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. CATHODE 8. CATHODE	STYLE 19: PIN 1. SOURCE 1 2. GATE 1 3. SOURCE 2 4. GATE 2 5. DRAIN 2 6. MIRROR 2 7. DRAIN 1 8. MIRROR 1	STYLE 20: PIN 1. SOURCE (N) 2. GATE (N) 3. SOURCE (P) 4. GATE (P) 5. DRAIN 6. DRAIN 7. DRAIN 8. DRAIN
STYLE 22: PIN 1. I/O LINE 1 2. COMMON CATHODE/VCC 3. COMMON CATHODE/VCC 4. I/O LINE 3 5. COMMON ANODE/GND 6. I/O LINE 4 7. I/O LINE 5 8. COMMON ANODE/GND	STYLE 23: PIN 1. LINE 1 IN 2. COMMON ANODE/GND 3. COMMON ANODE/GND 4. LINE 2 IN 5. LINE 2 OUT 6. COMMON ANODE/GND 7. COMMON ANODE/GND 8. LINE 1 OUT	STYLE 24: PIN 1. BASE 2. EMITTER 3. COLLECTOR/ANODE 4. COLLECTOR/ANODE 5. CATHODE 6. CATHODE 7. COLLECTOR/ANODE 8. COLLECTOR/ANODE
STYLE 26: PIN 1. GND 2. dv/dt 3. ENABLE 4. ILIMIT 5. SOURCE 6. SOURCE 7. SOURCE 8. VCC	STYLE 27: PIN 1. ILIMIT 2. OVLO 3. UVLO 4. INPUT+ 5. SOURCE 6. SOURCE 7. SOURCE 8. DRAIN	STYLE 28: PIN 1. SW_TO_GND 2. DASIC_OFF 3. DASIC_SW_DET 4. GND 5. V_MON 6. VBULK 7. VBULK 8. VIN
STYLE 30: PIN 1. DRAIN 1 2. DRAIN 1 3. GATE 2 4. SOURCE 2 5. SOURCE 1/DRAIN 2 6. SOURCE 1/DRAIN 2 7. SOURCE 1/DRAIN 2 8. GATE 1		
	PIN 1. N-SOURCE 2. N-GATE 3. P-SOURCE 4. P-GATE 5. P-DRAIN 6. P-DRAIN 7. N-DRAIN 8. N-DRAIN 8. N-DRAIN 8. N-DRAIN 8. N-DRAIN 8. SOURCE 4. GATE 5. DRAIN 6. DRAIN 7. CATHODE 8. CATHODE 8. CATHODE 8. CATHODE 8. CATHODE 8. CATHODE 9. COMMON CATHODE/VCC 9. COMMON CATHODE/VCC 1. I/O LINE 1 2. COMMON CATHODE/VCC 1. I/O LINE 3 5. COMMON ANODE/GND 6. I/O LINE 5 8. COMMON ANODE/GND 8. COMMON ANODE/GND 8. COMMON ANODE/GND 8. COMMON ANODE/GND 8. I/O LINE 5 8. COMMON ANODE/GND 8. SOURCE 9. I/O LINE 5 8. COMMON ANODE/GND 8. VILLE 26: PIN 1. GND 2. dv/dt 3. ENABLE 4. ILLIMIT 5. SOURCE 6. SOURCE 7. SOURCE 8. VCC 8. VCC 8. VCC 8. VCC 8. VCC 8. SOURCE 2 4. SOURCE 1/DRAIN 2 6. SOURCE 1/DRAIN 2 7. SOURCE 1/DRAIN 2 7. SOURCE 1/DRAIN 2	PIN 1. N-SOURCE 2. N-GATE 3. P-SOURCE 4. P-GATE 5. P-DRAIN 6. P-DRAIN 7. N-DRAIN 8. N-DRAIN 8. N-DRAIN 8. N-DRAIN 8. N-DRAIN 7. CATHODE, COMMON 8. N-DRAIN 8. CATHODE, COMMON 8. CATHODE 9IN 1. SOURCE 1 2. GATE 1 3. SOURCE 2 4. GATE 4. GATE 2 5. DRAIN 6. MIRROR 2 7. DRAIN 1 8. MIRROR 1 8. CATHODE 8. CATHODE 8. MIRROR 1 8. COMMON ANODE/GND 8. LINE 1 OUT 8. LINE 2 OUT 9. COMMON ANODE/GND 8. LINE 1 OUT 8. COMMON ANODE/GND 8. LINE 2 OUT 9. COMMON ANODE/GND 9. COMMON ANODE/GND 9. COMMON ANODE/GND 9. COMMON ANODE/GND 9. LINE 2 OUT 9. COMMON ANODE/GND 9. COMMON ANODE/GND 9. LINE 2 OUT 9. COMMON ANODE/GND 9. COMMON ANODE/GND 9. COMMON ANODE/GND 9. COMMON ANODE/GND 9. COMMON ANODE/

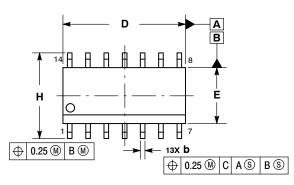
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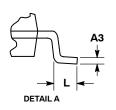
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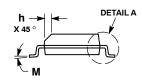


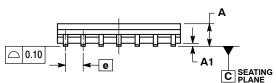
SOIC-14 NB CASE 751A-03 ISSUE L

DATE 03 FEB 2016









0.25 0.50 0.010 0.019 0.40 1.25 0.016 0.049

NOTES:
1. DIMENSIONING AND TOLERANCING PER

5. MAXIMUM MOLD PROTRUSION 0.15 PER

INCHES

MIN MAX

0.050 BSC

0.25 0.004 0.010

0.25 0.008 0.010

0.49 0.014

8.75 0.337 3.80 4.00 0.150 0.157

0.068

0.019

MILLIMETERS

MIN MAX

1.27 BSC

0.19

8.55

SIDE

Α

A1 0.10

АЗ

b 0.35

D E

e H h

ASME Y14.5M, 1994.
CONTROLLING DIMENSION: MILLIMETERS. DIMENSION b DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE PROTRUSION SHALL BE 0.13 TOTAL IN EXCESS OF AT MAXIMUM MATERIAL CONDITION.
4. DIMENSIONS D AND E DO NOT INCLUDE MOLD PROTRUSIONS.



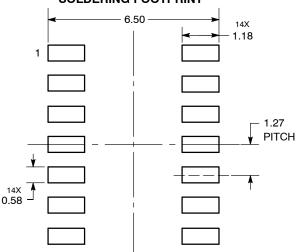
GENERIC

XXXXX = Specific Device Code Α = Assembly Location

WL = Wafer Lot Υ = Year = Work Week WW G = Pb-Free Package

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator. "G" or microdot " ■". may or may not be present.

SOLDERING FOOTPRINT*



DIMENSIONS: MILLIMETERS

STYLES ON PAGE 2

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^{*}For additional information on our Pb-Free strategy and soldering details, please download the ON Semiconductor Soldering and Mounting Techniques Reference Manual, SOLDERRM/D.

SOIC-14 CASE 751A-03 ISSUE L

DATE 03 FEB 2016

STYLE 1: PIN 1. COMMON CATHODE 2. ANODE/CATHODE 3. ANODE/CATHODE 4. NO CONNECTION 5. ANODE/CATHODE 6. NO CONNECTION 7. ANODE/CATHODE 8. ANODE/CATHODE 9. ANODE/CATHODE 10. NO CONNECTION 11. ANODE/CATHODE 12. ANODE/CATHODE 13. NO CONNECTION 14. COMMON ANODE	STYLE 2: CANCELLED	STYLE 3: PIN 1. NO CONNECTION 2. ANODE 3. ANODE 4. NO CONNECTION 5. ANODE 6. NO CONNECTION 7. ANODE 8. ANODE 9. ANODE 10. NO CONNECTION 11. ANODE 12. ANODE 13. NO CONNECTION 14. COMMON CATHODE	STYLE 4: PIN 1. NO CONNECTION 2. CATHODE 3. CATHODE 4. NO CONNECTION 5. CATHODE 6. NO CONNECTION 7. CATHODE 8. CATHODE 9. CATHODE 10. NO CONNECTION 11. CATHODE 12. CATHODE 13. NO CONNECTION 14. COMMON ANODE
STYLE 5: PIN 1. COMMON CATHODE 2. ANODE/CATHODE 3. ANODE/CATHODE 4. ANODE/CATHODE 5. ANODE/CATHODE 6. NO CONNECTION 7. COMMON ANODE 8. COMMON CATHODE 9. ANODE/CATHODE 10. ANODE/CATHODE 11. ANODE/CATHODE 12. ANODE/CATHODE 13. NO CONNECTION 14. COMMON ANODE	STYLE 6: PIN 1. CATHODE 2. CATHODE 3. CATHODE 4. CATHODE 5. CATHODE 6. CATHODE 7. CATHODE 8. ANODE 9. ANODE 10. ANODE 11. ANODE 12. ANODE 13. ANODE 14. ANODE	STYLE 7: PIN 1. ANODE/CATHODE 2. COMMON ANODE 3. COMMON CATHODE 4. ANODE/CATHODE 5. ANODE/CATHODE 6. ANODE/CATHODE 7. ANODE/CATHODE 8. ANODE/CATHODE 9. ANODE/CATHODE 10. ANODE/CATHODE 11. COMMON CATHODE 12. COMMON ANODE 13. ANODE/CATHODE 14. ANODE/CATHODE	STYLE 8: PIN 1. COMMON CATHODE 2. ANODE/CATHODE 3. ANODE/CATHODE 4. NO CONNECTION 5. ANODE/CATHODE 6. ANODE/CATHODE 7. COMMON ANODE 8. COMMON ANODE 9. ANODE/CATHODE 10. ANODE/CATHODE 11. NO CONNECTION 12. ANODE/CATHODE 13. ANODE/CATHODE 14. COMMON CATHODE

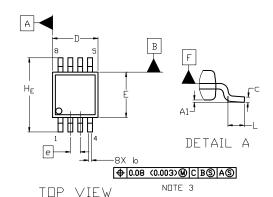
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DESCRIPTION:	SOIC-14 NB		PAGE 2 OF 2

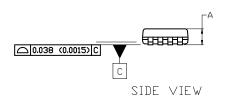
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Micro8 CASE 846A-02 ISSUE K

DATE 16 JUL 2020

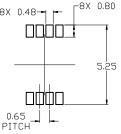






NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2009.
- CONTROLLING DIMENSION: MILLIMETERS
- DIMENSION 6 DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE PROTRUSION SHALL BE 0.10 mm IN EXCESS OF MAXIMUM MATERIAL CONDITION.
- DIMENSIONS D AND E DO NOT INCLUDE MOLD FLASH, PROTRUSION OR GATE BURRS. MOLD FLASH, PROTRUSIONS, OR GATE BURRS SHALL NOT EXCEED 0.15 mm PER SIDE. DIMENSION E DDES NOT INCLUDE INTERLEAD FLASH OR PROTRUSION. INTERLEAD FLASH OR PROTRUSION SHALL NOT EXCEED 0.25 mm PER SIDE. DIMENSIONS D AND E ARE DETERMINED AT DATUM F.
- DATUMS A AND B ARE TO BE DETERMINED AT DATUM F.
- A1 IS DEFINED AS THE VERTICAL DISTANCE FROM THE SEATING PLANE TO THE LOWEST POINT ON THE PACKAGE BODY.



RECOMMENDED MOUNTING FOOTPRINT

MID	MILLIMETERS		
DIM	MIN.	N□M.	MAX.
Α	-	-	1.10
A1	0.05	0.08	0.15
b	0.25	0.33	0.40
С	0.13	0.18	0.23
D	2.90	3.00	3.10
E	2.90	3.00	3.10
e	0.65 BSC		
HE	4.75	5.05	
L	0.40	0.55	0.70

GENERIC MARKING DIAGRAM*



XXXX = Specific Device Code Α = Assembly Location

Υ = Year W = Work Week = Pb-Free Package

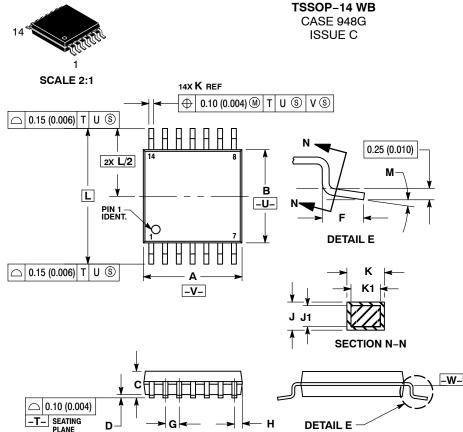
(Note: Microdot may be in either location)

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot "■", may or may not be present. Some products may not follow the Generic Marking.

STYLE 1:	STYLE 2:	STYLE 3:
PIN 1. SOURCE	PIN 1. SOURCE 1	PIN 1. N-SOURCE
SOURCE	2. GATE 1	2. N-GATE
SOURCE	3. SOURCE 2	P-SOURCE
GATE	4. GATE 2	4. P-GATE
DRAIN	5. DRAIN 2	5. P-DRAIN
DRAIN	6. DRAIN 2	6. P-DRAIN
7. DRAIN	7. DRAIN 1	7. N-DRAIN
8. DRAIN	8. DRAIN 1	8. N-DRAIN

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DATE 17 FEB 2016

- NOTES.

 1. DIMENSIONING AND TOLERANCING PER ANSI Y14.5M, 1982.

 2. CONTROLLING DIMENSION: MILLIMETER.

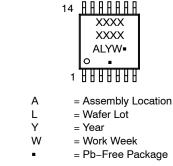
 3. DIMENSION A DOES NOT INCLUDE MOLD
- FLASH, PROTRUSIONS OR GATE BURRS. MOLD FLASH OR GATE BURRS SHALL NOT EXCEED 0.15 (0.006) PER SIDE.
 DIMENSION B DOES NOT INCLUDE
- INTERLEAD FLASH OR PROTRUSION.
 INTERLEAD FLASH OR PROTRUSION SHALL
- INTERLEAD FLASH OR PROTRUSION SHALL NOT EXCEED 0.25 (0.010) PER SIDE.

 5. DIMENSION K DOES NOT INCLUDE DAMBAR PROTRUSION. ALLOWABLE DAMBAR PROTRUSION SHALL BE 0.08 (0.003) TOTAL IN EXCESS OF THE K DIMENSION AT MAXIMUM MATERIAL CONDITION.

 6. TERMINAL NUMBERS ARE SHOWN FOR DEFERENCE ONLY.
- REFERENCE ONLY.
 DIMENSION A AND B ARE TO BE
 DETERMINED AT DATUM PLANE -W-.

	MILLIMETERS		INCHES	
DIM	MIN	MAX	MIN	MAX
Α	4.90	5.10	0.193	0.200
В	4.30	4.50	0.169	0.177
С	-	1.20		0.047
D	0.05	0.15	0.002	0.006
F	0.50	0.75	0.020	0.030
G	0.65	BSC	0.026	BSC
Н	0.50	0.60	0.020	0.024
J	0.09	0.20	0.004	0.008
J1	0.09	0.16	0.004	0.006
K	0.19	0.30	0.007	0.012
K1	0.19	0.25	0.007	0.010
L	6.40		0.252	
М	° o	8 °	0 °	8 °

GENERIC MARKING DIAGRAM*



(Note: Microdot may be in either location)

*This information is generic. Please refer to device data sheet for actual part marking. Pb-Free indicator, "G" or microdot " ■", may or may not be present.

—	7.06
1	
	
	U 0.65 PITCH
, <u> </u>	<u> </u>
14X	
0.36 14X 1.26	DIMENSIONS: MILLIMETERS

SOLDERING FOOTPRINT

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